Claim 8 (Twice Amended). An electronic system including an integrated circuit having a built-in self-test arrangement therein, said integrated circuit including

means for storing test instructions including means for discriminating a source of a test command for performing manufacturing level and board level testing and receiving test instructions provided from an external tester,

means for generating default test instructions in absence of instructions from an external tester, and

means for supplying said default test instructions to said means for storing test instructions.

REMARKS

Applicant noted with appreciation an approval of the formal drawings and specification corrections.

Claims 1-17 are currently pending in the application. By this amendment, claims 1 and 8 are amended to clarify difference between the reference and the present invention. Support for the amendments is provided in at least Figure 1 and at page 15, lines 15-19 of the present specification. No new matter is added. Reconsideration of the rejected claims in view of the above amendments and the following remarks is respectfully requested.

Claims 1-17 were rejected under 35 U.S.C. §102(e) as being anticipated by Schwartz (U.S. Patent No.5,982,681). This rejection is respectfully traversed.

As it was discussed previously Applicant resolves the problem of providing a testing of storage cells at different stages of manufacturing of board assembly and during system operation by modifying the BIST structure. All structures involved into the testing is incorporated into BIST. In contrast, the reference to Schwarz focuses on developing the flexibility of the system for providing debugging and the system is created separately from BIST. Specifically, referring to Figure 2 of the reference, the buffer (206), multiplexers (202, 204), and comparator (106) are structural elements which are located separate from the BIST (104). Therefore, it should be understood that what we are talking here about is a different level of integration in the Applicant's invention. Additionally, the ability of the Applicant's system to discriminate between